

W24L04



512K × 8 CMOS STATIC RAM

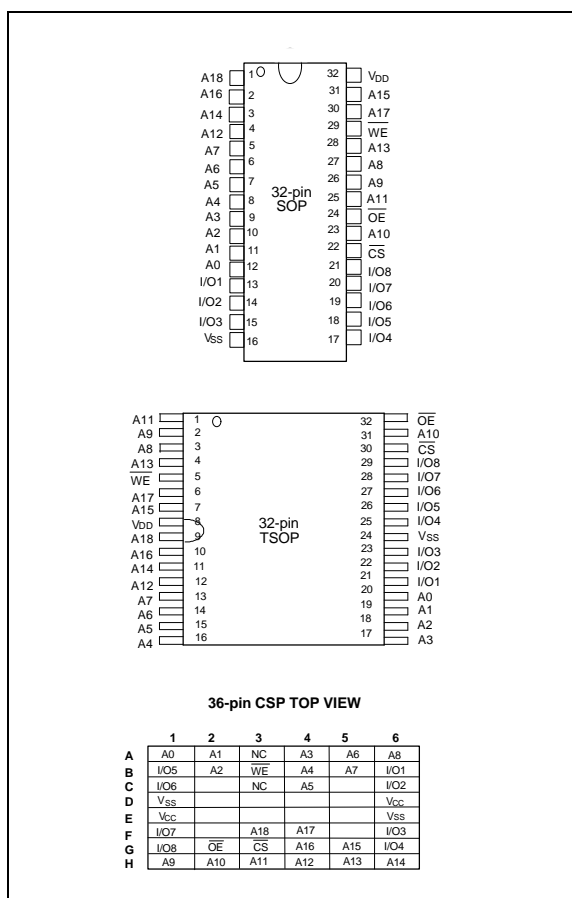
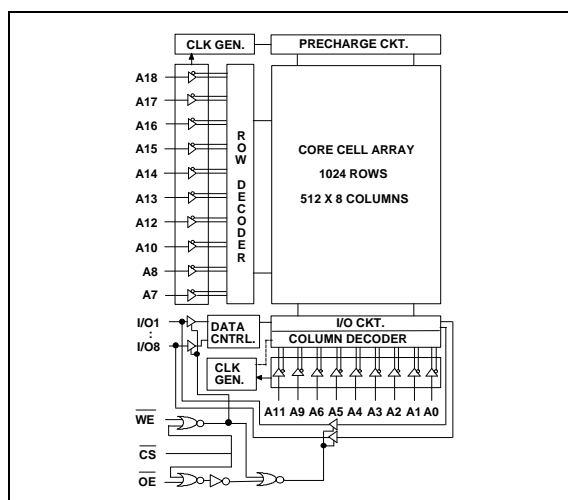
GENERAL DESCRIPTION

The W24L04 is a normal-speed, very low-power CMOS static RAM organized as 524288 × 8 bits that operates on a wide voltage range from 2.7V to 3.3V power supply. The W24L04, W24L04-LE and W24L04-LI, can meet the requirement of various operating temperature. This device is manufactured using Winbond's high performance CMOS technology.

FEATURES

- Low power consumption
- Access time: 70 nS
- 2.7V to 3.3V supply voltage
- Fully static operation
- All inputs and outputs directly TTL compatible
- Three-state outputs
- Battery back-up operation capability
- Data retention voltage: 1.5V (min.)
- Packaged in 32-pin 450 mil SOP, standard type one TSOP (8 mm × one TSOP (8 mm 13.4 mm) and 36 pin CSP

BLOCK DIAGRAM



PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0–A18	Address Inputs
I/O1–I/O8	Data Inputs/Outputs
CS	Chip Select Input
WE	Write Enable Input
OE	Output Enable Input
VDD	Power Supply
VSS	Ground
NC	No Connection



TRUTH TABLE

CS	OE	WE	MODE	I/O1- I/O8	VDD CURRENT
H	X	X	Not Selected	High Z	ISB, ISB1
L	H	H	Output Disable	High Z	IDD
L	L	H	Read	Data Out	IDD
L	X	L	Write	Data In	IDD

DC CHARACTERISTICS

Absolute Maximum Ratings

PARAMETER		RATING	UNIT
Supply Voltage to VSS Potential		-0.5 to +4.6	V
Input/Output to VSS Potential		-0.5 to VDD +0.5	V
Allowable Power Dissipation		1.0	W
Storage Temperature		-65 to +150	°C
Operating Temperature	LE	-20 to 85	°C
	LI	-40 to 85	°C

Note: Exposure to conditions beyond those listed under Absolute Maximum Ratings may adversely affect the life and reliability of the device.

Operating Characteristics

(VSS = 0V; TA (°C) = -20 to 85 for LE, -40 to 85 for LI)

PARAMETER	SYM.	TEST CONDITIONS	W24L04		UNIT
			MIN.	MAX.	
Operating Power Voltage	VDD	-	2.7	3.3	V
Input Low Voltage	VIL	-	-0.2	+0.4	V
Input High Voltage	VIH	-	+2.2	VDD +0.3	V
Input Leakage Current	ILI	VIN = VSS to VDD	-1	+1	μA
Output Leakage Current	ILO	V _{I/O} = VSS to VDD CS = VIH (min.) or OE = VIH (min.) or WE = VIL (max.)	-1	+1	μA
Output Low Voltage	VOL	IOL = +2.1 mA	-	0.4	V
Output High Voltage	VOH	IOH = -1.0 mA	2.4	-	V



Operating Characteristics, continued

PARAMETER	SYM.	TEST CONDITIONS	W24L04		UNIT
			MIN.	MAX.	
Operating Power Supply Current	I _{DD}	$\overline{CS} = V_{IL} \text{ (max.)}$ I/O = 0 mA Cycle = min. Duty = 100%	-	40	mA
Standby Power Supply Current	I _{SB}	$\overline{CS} = V_{IH} \text{ (min.)}$ Duty = 100%	-	0.3	mA
	I _{SB1}	$\overline{CS} \geq V_{DD} - 0.2V$	-	5	μA

CAPACITANCE

(T_A = 25° C, f = 1 MHz)

PARAMETER	SYM.	CONDITIONS	MAX.	UNIT
Input Capacitance	C _{IN}	V _{IN} = 0V	8	pF
Input/Output Capacitance	C _{I/O}	V _{OUT} = 0V	10	pF

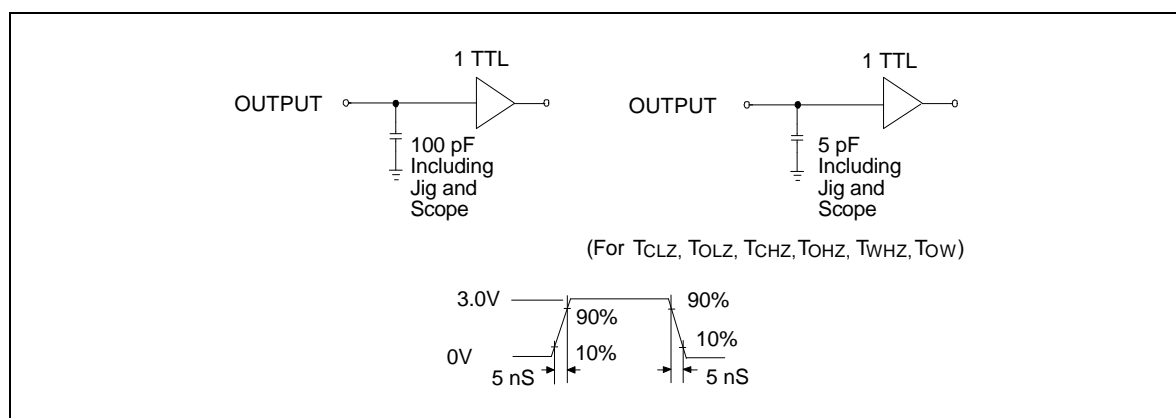
Note: These parameters are sampled but not 100% tested.

AC CHARACTERISTICS

AC Test Conditions

PARAMETER	CONDITIONS
Input Pulse Levels	0V to 3.0V
Input Rise and Fall Times	5 nS
Input and Output Timing Reference Level	1.5V
Output Load	See the drawing below

AC Test Loads and Waveform





AC Characteristics, continued

(V_{SS} = 0V; T_A (°C) = -20 to 85 for LE, -40 to 85 for LI)**Read Cycle**

PARAMETER	SYM.	W24L04		UNIT
		MIN.	MAX.	
Read Cycle Time	TRC	70	-	nS
Address Access Time	TAA	-	70	nS
Chip Select Access Time	TACS	-	70	nS
Output Enable to Output Valid	TAOE	-	35	nS
Chip Selection to Output in Low Z	TCLZ*	5	-	nS
Output Enable to Output in Low Z	TOLZ*	3	-	nS
Chip Deselection to Output in High Z	TCHZ*	-	30	nS
Output Disable to Output in High Z	TOHZ*	-	30	nS
Output Hold from Address Change	TOH	10	-	nS

*These parameters are sampled but not 100% tested

Write Cycle

PARAMETER	SYM.	W24L04		UNIT
		MIN.	MAX.	
Write Cycle Time	TWC	70	-	nS
Chip Selection to End of Write	TCW	60	-	nS
Address Valid to End of Write	TAW	60	-	nS
Address Setup Time	TAS	0	-	nS
Write Pulse Width	TWP	55	-	nS
Write Recovery Time	\overline{CS} , \overline{WE} TWR	0	-	nS
Data Valid to End of Write	TDW	40	-	nS
Data Hold from End of Write	TDH	0	-	nS
Write to Output in High Z	TWHZ*	-	30	nS
Output Active from End of Write	TOW	5	-	nS

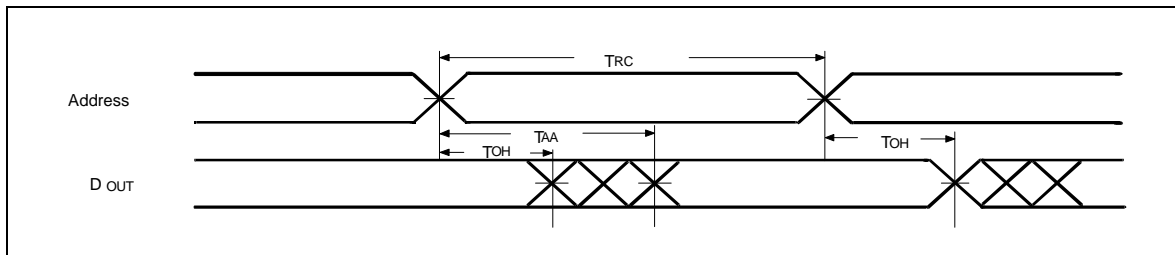
*These parameters are sampled but not 100% tested



TIMING WAVEFORMS

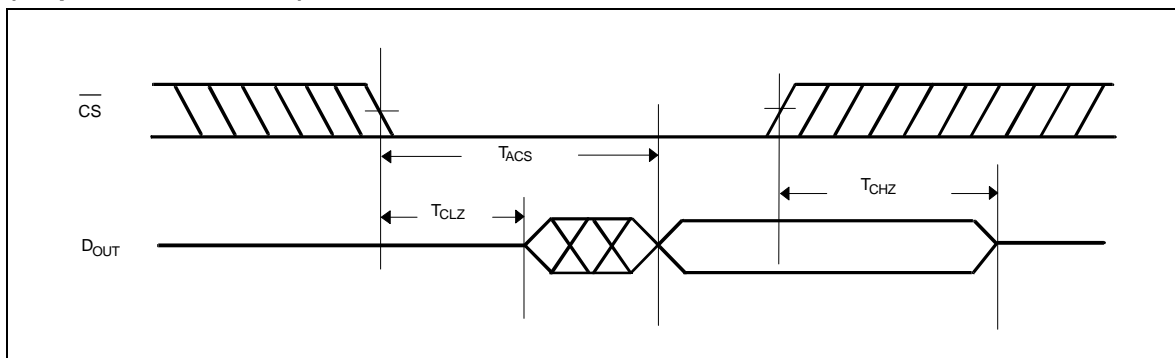
Read Cycle 1

(Address Controlled)



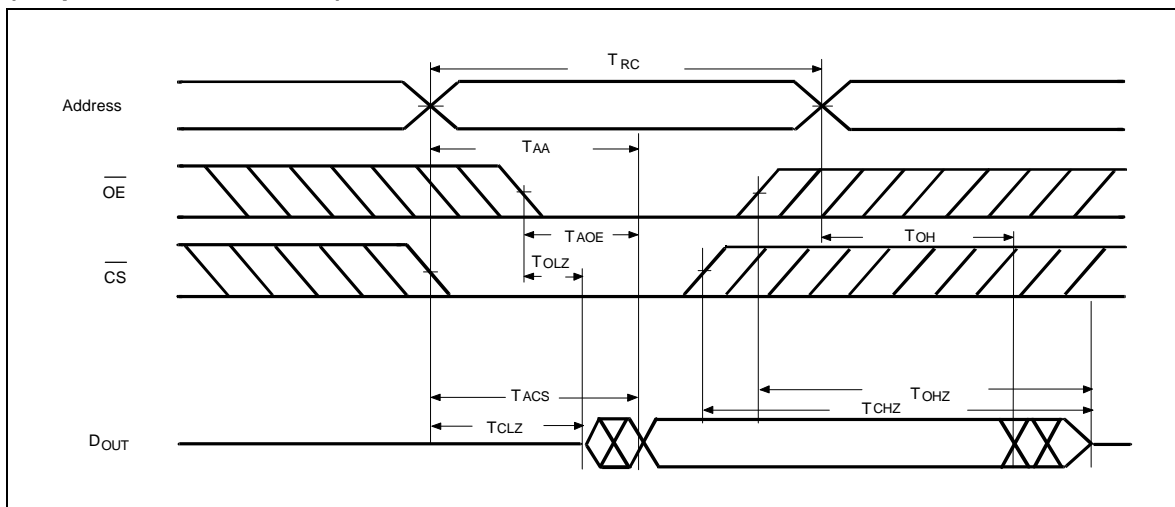
Read Cycle 2

(Chip Select Controlled)



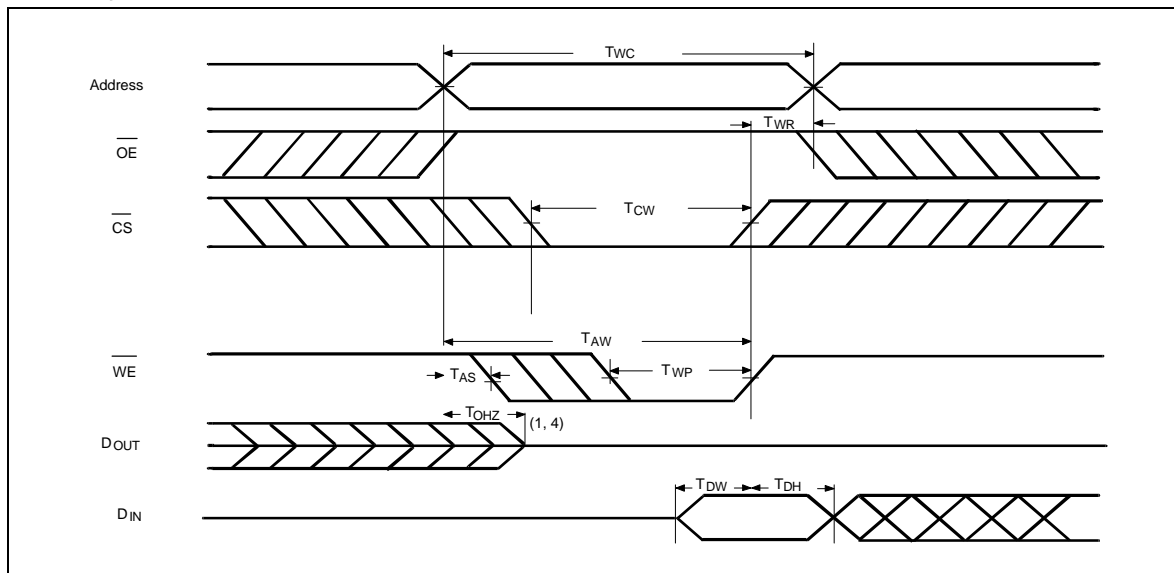
Read Cycle 3

(Output Enable Controlled)



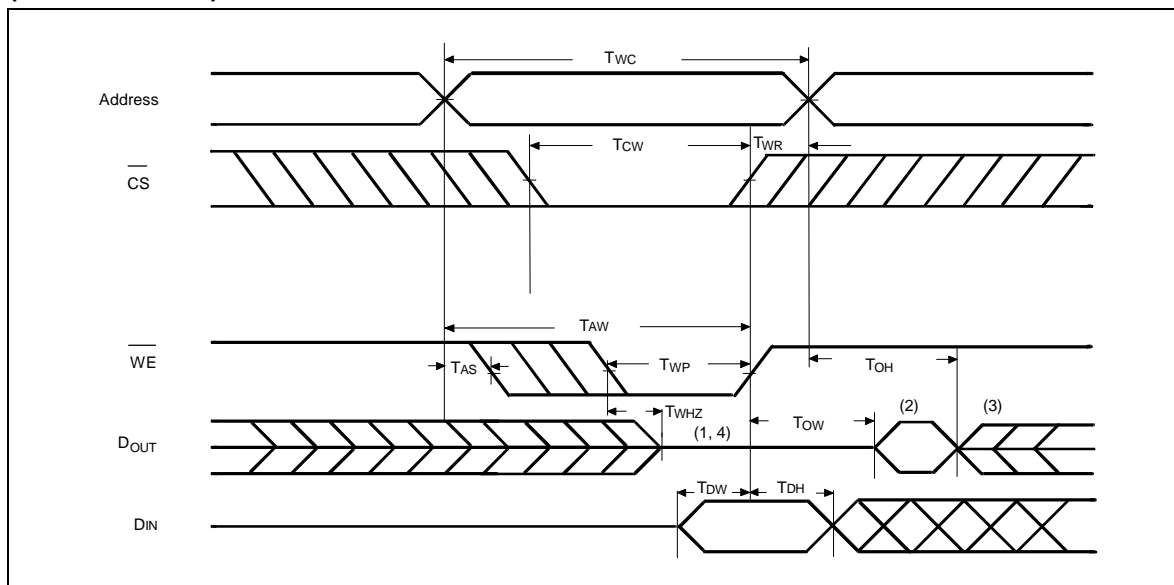
Timing Waveforms, continued

Write Cycle 1



Write Cycle 2

($\overline{OE} = V_{IL}$ Fixed)



Notes:

1. During this period, I/O pins are in the output state, so input signals of opposite phase to the outputs should not be applied.
2. The data output from DOUT are the same as the data written to DIN during the write cycle.
3. DOUT provides the read data for the next address.
4. Transition is measured ± 500 mV from steady state with $C_L = 5$ pF. This parameter is guaranteed but not 100% tested.

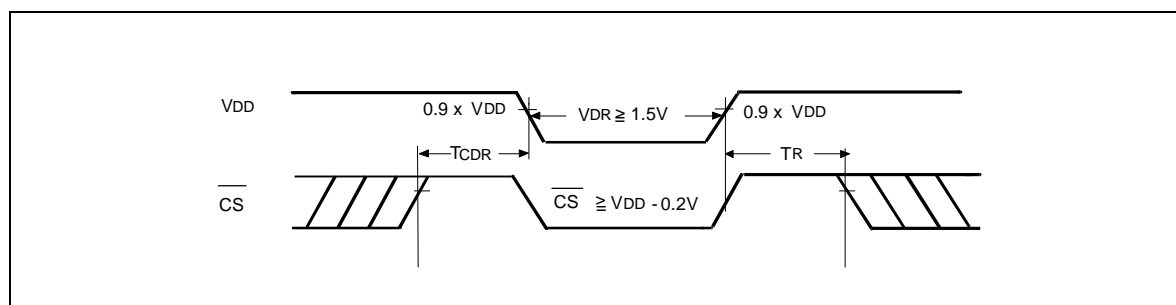
DATA RETENTION CHARACTERISTICS

(T_A (°C) = -20 to 85 for LE; -40 to 85 for LI)

PARAMETER	SYM.	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
VDD for Data Retention	VDR	$\overline{CS} \geq V_{DD} - 0.2V$	1.5	-	-	V
Data Retention Current	I _{DDDR}	$\overline{CS} \geq V_{DD} - 0.2V, V_{DD} = 3.0V$	-	-	5	μA
Chip Deselect to Data Retention Time	T _{CDR}	See data retention waveform	0	-	-	nS
Operation Recovery Time	T _R		T _{RC} *	-	-	nS

* Read Cycle Time

DATA RETENTION WAVEFORM





ORDERING INFORMATION

PART NO.	ACCESS TIME (nS)	OPERATING VOLTAGE (V) / STANDBY CURRENT (μ A)	OPERATING TEMPERATURE ($^{\circ}$ C)	PACKAGE
W24L04B-70LE	70	3V / 5 μ A	-20 to 85	CSP
W24L04Q-70LE	70	3V / 5 μ A	-20 to 85	Small type one TSOP
W24L04S-70LE	70	3V / 5 μ A	-20 to 85	450 mil SOP
W24L04T-70LE	70	3V / 5 μ A	-20 to 85	Standard type one TSOP
W24L04B-70LI	70	3V / 5 μ A	-40 to 85	CSP
W24L04Q-70LI	70	3V / 5 μ A	-40 to 85	Small type one TSOP
W24L04S-70LI	70	3V / 5 μ A	-40 to 85	450 mil SOP
W24L04T-70LI	70	3V / 5 μ A	-40 to 85	Standard type one TSOP
W24L04B-70LL	70	3V / 20 μ A	0 to 70	CSP
W24L04Q-70LL	70	3V / 20 μ A	0 to 70	Small type one TSOP
W24L04S-70LL	70	3V / 20 μ A	0 to 70	450 mil SOP
W24L04T-70LL	70	3V / 20 μ A	0 to 70	Standard type one TSOP

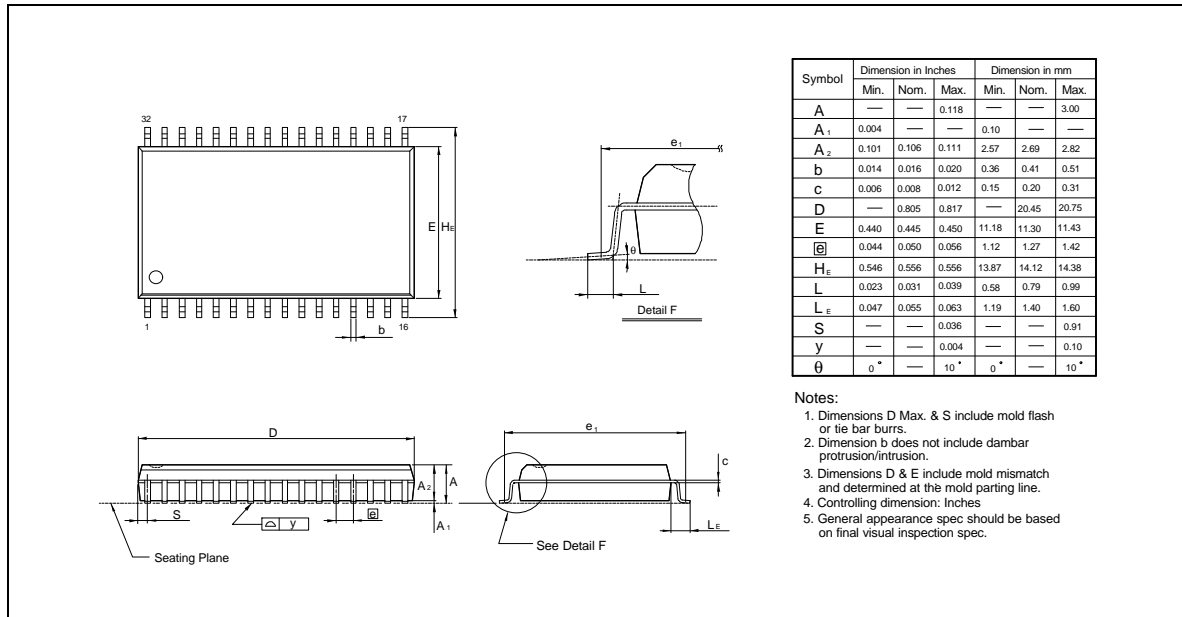
Notes:

1. Winbond reserves the right to make changes to its products without prior notice.
2. Purchasers are responsible for performing appropriate quality assurance testing on products intended for use in applications where personal injury might occur as a consequence of product failure.

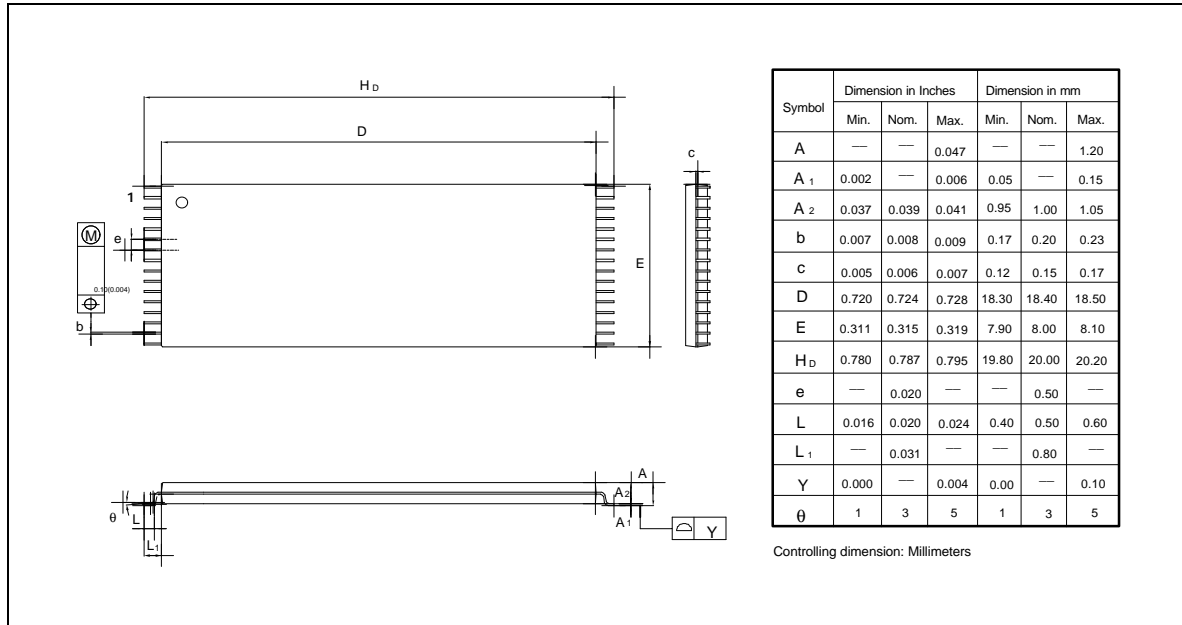


PACKAGE DIMENSIONS

32-pin SOP Wide Body



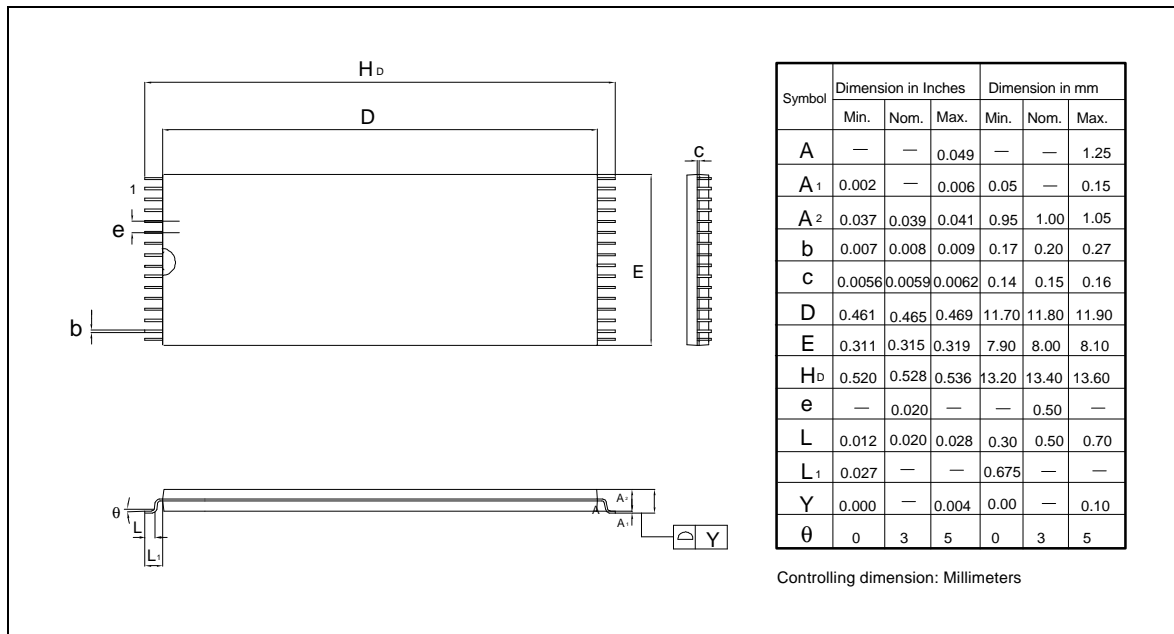
32-pin Standard Type One TSOP





Package Dimensions, continued

32-pin Small Type One TSOP





VERSION HISTORY

VERSION	DATE	PAGE	DESCRIPTION
A1	Oct. 1999	-	Initial Issued
A2	Jan. 2000	1, 2, 3, 4, 8	W24L04 becomes W24L04 (2.7V–3.3V, 70 nS) A2 revision & W24V04 (2.3V–2.7V, 85 nS) A1 preliminary revision. Change the Operation Voltage & Access Time.



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Note: All data and specifications are subject to change without notice.